

Defect-oriented library builder and hierarchical test generation

Cibakova, Tatiana; Gramatova, Elena; Kuzmicz, W.; Pleskacz, Witold A.; **Raik, Jaan; Ubar, Raimund-Johannes** IEEE Design and Diagnostics of Electronic Circuits and Systems - IEEE DDECS 2001 : Fourth International Workshop on IEEE Design and Diagnostics of Electronic Circuits and Systems : Győr, Hungary, April 18-20, 2001 2001 / p. 163-168 : ill

Fast and efficient static compaction of test sequences based on greedy algorithms

Raik, Jaan; Jutman, Artur; Ubar, Raimund-Johannes IEEE Design and Diagnostics of Electronic Circuits and Systems - IEEE DDECS 2001 : Fourth International Workshop on IEEE Design and Diagnostics of Electronic Circuits and Systems : Győr, Hungary, April 18-20, 2001 2001 / p. 117-122 https://slideplayer.com/slide/9971880/#google_vignette

Internet based test generation and fault simulation

Ivask, Eero; Ubar, Raimund-Johannes; Raik, Jaan; Schneider, Andre IEEE Design and Diagnostics of Electronic Circuits and Systems - IEEE DDECS 2001 : Fourth International Workshop on IEEE Design and Diagnostics of Electronic Circuits and Systems : Győr, Hungary, April 18-20, 2001 2001 / p. 57-60 : ill